	ABLE CO	under:	35 U.S.C. 371	B	ISSUE DATE
	U.S. UTILITY P	atent Ap	plication		
APPL NUM 10018708	FILING DATE 04/15/2002	CLASS 451	SUBCLASS	GAU 3723	EXAMINER Wilso
**APPLICANT				ajima Kaz	utaka; Tsuji Masahiro; Takag
Hideki; isnikav	va Shigeharu; Yası	uua miioy	uki,		
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Foreign priority of					P3p2000078US/2369NP
35 USC 119 cond Verified and Ackr	nowledged Examiners's				sotnog of manufacturing
35 USC 119 cond Verified and Ackr	of wafer polisher,	method o	f polishing wat	fer, and m	U.S.DEPT OF COMM /PAT & TM-PTO-4

NOTICE OF ALLOWANCE MAILED			CEAIMS ALLOWED			
		Assistant Examiner	Total Claims		Print Claim for O.G	
ISSUE FEE			DRAWING			
Amount Due	Date Paid		Sheets Drwg.	Figs.Dr#g	g. Print Fig.	
		Primary Examiner				
TERMINAL DISCLAMER		PREPARED FOR ISSUE	Application Examiner			
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